WHAT IS CLAIMED IS:

- 1. A method for measuring the lifetime of an excited state in a specimen, coprises the following steps:
 - generating an exciting light pulse and an emitting light pulse;
 - illuminating the specimen with the exciting light pulse;
 - illuminating the specimen with the emitting light pulse at a predefined time offset from illuminating the specimen with the exciting light pulse;
 - detecting the power level of the luminescent light emerging from the specimen;
 - repeating the first four steps with different time offsets; and
 - determining the lifetime of the excited state of the specimen as a function of the power level of the luminescent light emerging from the specimen and the time offset.
- 2. The method as defined in Claim 1, wherein the exciting light pulse is generated with a pulsed laser, and the emitting light pulse with a further pulsed laser and both pulsed lasers are synchronized with one another.
- 3. The method as defined in Claim 1, wherein the exciting light pulse and the emitting light pulse are generated by a single pulsed laser.
- 4. The method as defined in Claim 1, comprises one further step:
 - reducing the energy of the emitting light pulse in proportion to the energy of the exciting light pulse.
- 5. The method as defined in Claim 4, wherein this is achieved with an optically parametric oscillator that is provided in the beam path of the emitting light pulse.

- 6. The method as defined in Claim 1, wherein the luminescent light is fluorescent light.
- 7. The method as defined in Claim 1, wherein the specimen is a microscopic sample equipped with fluorescent dyes.
- 8. The method as defined in Claim 1, wherein light of the wavelength of the emitting light pulse is not detected.
- 9. An apparatus for measuring the lifetime of an excited state in a specimen, wherein the apparatus comprises an electromagnetic energy source that emits light of one wavelength, a means for dividing the light into at least a first and a second partial light beam and an intermediate element in at least one partial light beam to influence the time of travel of the at least one partial light beam.
- 10. The apparatus as defined in Claim 9, wherein the first partial light beam is an exciting light beam directed onto a specimen, and excites a defined subregion there.
- 11. The apparatus as defined in Claim 10, wherein the second partial light beam defines an emitting light beam and is directed onto the specimen in such a way that the subregion of the specimen is at least partially overlapped.
- 12. The apparatus as defined in Claim 9, wherein the intermediate element modifies the length of the optical light path.

- 13. The apparatus as defined in Claim 12 wherein the intermediate element is configured movably and thereby defines a chicane having an adjustable passage length.
- 14. The apparatus as defined in Claim 9, wherein an element for wavelength modification is provided in one partial light beam.
- 15. The apparatus as defined in Claim 14, wherein the element for wavelength modification is an optically parametric oscillator or an element for frequency multiplication.
- 16. The apparatus as defined in Claim 10, wherein the excitation is multi-photon excitation.
- 17. The apparatus as defined in Claim 9, wherein the electromagnetic energy source is a laser.
- 18. The apparatus as defined in Claim 19, wherein the electromagnetic energy source is a pulsed laser.
- 19. A scanning microscope comprising a device for generating a relative motion between an illuminating light beam and a specimen, a microscope optical system, a detector and an apparatus for measuring the lifetime of an excited state in a specimen.
- 20. The scanning microscope as defined in claim 19 wherein the apparatus for measuring the lifetime of an excited state in a specimen has an electromagnetic energy source that emits light of one wavelength, a means for dividing the light into at least a first and a second partial light beam and an intermediate element in at least one partial light beam to influence the time of travel of the at least one partial light beam.